

Notice of References CitedApplication/Control No.
09/901,364Applicant(s)/Patent Under
Reexamination
DEARNALEY ET AL.Examiner
Andrew L. OltmansArt Unit
1742

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hay et al., "Instrumented Indentation Testing", ASM Handbook, Volume 8, ASM Handbook Committee, 2000, pages 1-15.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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